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Industrial automation systems and integration — Product data representation and exchange —

Part 332:

Abstract test suite: Technical data packaging core information and exchange

Systèmes d'automatisation industrielle et intégration — Représentation et échange de données de produits —

Partie 332: Suite d'essai abstrait: Paquet de données techniques

ISO/TS 10303-332:2002



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ISO/TS 10303-332:2002

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 3.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

In other circumstances, particularly when there is an urgent market requirement for such documents, a technical committee may decide to publish other types of normative document:

- an ISO Publicly Available Specification (ISO/PAS) represents an agreement between technical experts in an ISO working group and is accepted for publication if it is approved by more than 50 % of the members of the parent committee casting a vote;
- an ISO Technical Specification (ISO/TS) represents an agreement between the members of a technical committee and is accepted for publication if it is approved by 2/3 of the members of the committee casting a vote.

An ISO/PAS or ISO/TS is reviewed every three years with a view to deciding whether it can be transformed into an International Standard.

Attention is drawn to the possibility that some of the elements of this part of ISO 10303 may be the subject of patent rights. ISO shall not be held responsible for any or all such patent rights.

ISO/TS 10303-323 was prepared by Technical Committee ISO/TC 184, *Industrial automation systems and integration*, Subcommittee SC 4, *Industrial data*.

This International Standard is organised as a series of parts, each published separately. The structure of this International Standard is described in ISO 10303-1.

Each part of this International Standard is a member of one of the following series: description methods, implementation methods, conformance testing methodology and framework, integrated generic resources, integrated application resources, application protocols, abstract test suites, application interpreted constructs, and application modules. This part is a member of the abstract test suite series.

A complete list of parts of ISO 10303 is available from the Internet:

<http://www.nist.gov/sc4/editing/step/titles/>

Annexes A, B and C form a normative part of this part of ISO 10303. Annexes D and E are for information only.

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Introduction

ISO 10303 is an International Standard for the computer-interpretable representation of product information and for the exchange of product data. The objective is to provide a neutral mechanism capable of describing products throughout their life cycle. This mechanism is suitable not only for neutral file exchange, but also as a basis for implementing and sharing product databases, and as a basis for archiving.

This part of ISO 10303 specifies the abstract test suite for ISO 10303-232, Application protocol: Technical data packaging core information and exchange. The abstract test cases presented here are the basis for conformance testing of implementations of ISO 10303-232.

The purpose of an abstract test suite is to provide a basis for evaluating whether a particular implementation of an application protocol actually conforms to the requirements of that application protocol. A standard abstract test suite helps ensure that evaluations of conformance are conducted in a consistent manner by different test laboratories.

This abstract test suite is made up of two major parts:

- the test purposes, the specific items to be covered by conformance testing;
- the set of abstract test cases that meet those test purposes.

The test purposes are statements of the application protocol requirements that are to be addressed by the abstract test cases. Test purposes are derived primarily from the application protocol's information requirements and AIM, as well as from other sources such as standards referenced by the application protocol and requirements stated in the application protocol conformance requirements clause.

The abstract test cases address the test purposes by:

- specifying the requirements for input data to be used when testing an implementation of the application protocol;
- specifying the verdict criteria to be used when evaluating whether the implementation successfully converted the input data to a different form.

The abstract test cases set the requirements for the executable test cases that are required to actually conduct a conformance test. Executable test cases contain the scripts, detailed values, and other explicit information required to conduct a conformance test on a specific implementation of the application protocol.

At the time of publication of this document, conformance testing requirements had been established for implementations of application protocols in combination with ISO 10303-21 and ISO 10303-22. This part of ISO 10303 only specifies test purposes and abstract test cases for a subset of such implementations.

NOTE ISO TC184/SC4 has prepared Standing Documents [1] and [2] for documenting abstract test suites that are prepared as International Standards. Subsequent ISO TC184/SC4 resolutions allow abstract test suites to be prepared as Technical Specifications. This part of ISO 10303 was documented as a Technical Specification using the ISO TC184/SC4 Standing Documents [1] and [2] as a guide. Primary reliance was placed on [2].

Portions of this part of ISO 10303 that relied on [1] are identified in NOTEs in the appropriate clause or subclause. Technical differences in documentation of abstract test suites from the Standing Documents [1] and [2] are identified in NOTEs throughout this part of ISO 10303. Editorial differences in documentation are not identified in this part of ISO 10303.

For ISO 10303-21, two kinds of implementations, preprocessors and postprocessors, must be tested. Both these are addressed in this abstract test suite.

For ISO 10303-22, a class of applications will possess the capability to upload and download AP-compliant SDAI-models or schema instances to and from applications that implement the SDAI. By providing test case data that correspond with SDAI-models, this abstract test suite addresses such applications in a single-schema scenario.

iTeh Standards (https://standards.iteh.ai) Document Preview

ISO/TS 10303-332:2002

Industrial automation systems and integration — Product data representation and exchange — Part 332:

Abstract test suite: Technical data packaging core information and exchange

1 Scope

This part of ISO 10303 specifies the abstract test suite to be used in the conformance testing of implementations of ISO 10303-232. The following are within the scope of this part of ISO 10303:

- the specification of the test purposes associated with ISO 10303-232;
- the verdict criteria to be applied during conformance testing of an implementation of ISO 10303-232 using ISO 10303-21 or ISO 10303-22;

NOTE The verdict criteria are used to ascertain whether a test purpose has been satisfactorily met by an implementation under test (IUT) within the context of a given test case.

— the abstract test cases to be used as the basis for the executable test cases for conformance testing.

The following are outside the scope of this part of ISO 10303:

- the creation of executable test cases;
- test specifications for tests other than conformance testing such as interoperability or acceptance 32-2002 testing;
 - other implementation methods.

2 Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this part of ISO 10303. For dated references, subsequent amendments to, or revisions of, any of these publications do not apply. However, parties to agreements based on this part of ISO 10303 are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. For undated references, the latest edition of the normative document referred to applies. Members of ISO and IEC maintain registers of currently valid International Standards.

ISO 10303-1:1994, Industrial automation systems and integration — Product data representation and exchange — Part 1: Overview and fundamental principles

ISO 10303-11:1994, Industrial automation systems and integration — Product data representation and exchange — Part 11: Description methods: The EXPRESS language reference manual

ISO 10303-21:2002, Industrial automation systems and integration — Product data representation and exchange — Part 21: Implementation methods: Clear text encoding of the exchange structure

ISO 10303-22:1998, Industrial automation systems and integration — Product data representation and exchange — Part 22: Implementation methods: Standard data access interface

ISO 10303-31:1994, Industrial automation systems and integration — Product data representation and exchange — Part 31: Conformance testing methodology and framework: General concepts

ISO 10303-32:1998, Industrial automation systems and integration — Product data representation and exchange — Part 32: Conformance testing methodology and framework: Requirements on testing laboratories and clients

ISO 10303-34:2001, Industrial automation systems and integration — Product data representation and exchange — Part 34: Conformance testing methodology and framework: Abstract test methods for application protocol implementations

ISO 10303-232:2002, Industrial automation systems and integration — Product data representation and exchange — Part 232: Application protocol: Technical data packaging core information and exchange

ISO/IEC 8824-1:1998, Information technology — Abstract Syntax Notation One (ASN.1): Specification of basic notation

3 Terms, definitions, and abbreviations

3.1 Terms defined in ISO 10303-1

For the purpose of this part of ISO 10303, the following terms defined in ISO 10303-1 apply.

- abstract test suite (ATS);
- application protocol (AP);
- implementation method.

3.2 Terms defined in ISO 10303-31

For the purpose of this part of ISO 10303, the following terms defined in ISO 10303-31 apply.

- abstract test case (ATC);
- conformance testing;
- executable test case;
- implementation under test (IUT);
- postprocessor;
- preprocessor;

— verdict criterion.
3.3 Terms defined in ISO 10303-232
For the purpose of this part of ISO 10303, the following terms defined in ISO 10303-232 apply.
— associated list;
— data definition exchange (DDE);
— data list;
— indentured data list;
— index list;
— parts list;
- TDP element; iTeh Standards
— technical data package (TDP). (nttps://standards.iteh.ai)
3.4 Other terms and definitions
For the purposes of this part of ISO 10303, the following definitions apply.
3.4.1 application element standards/iso/3109229a-1796-4e6d-8cdb-9a8699ecbb0a/iso-ts-10303-332-20 an application object, attribute, or assertion defining the information requirements in clause 4 of an application protocol.
3.4.2application element test purposea test purpose derived from the application elements in the ARM of an application protocol.
3.4.3 application interpreted model test purpose

3.4.4

domain test purpose

— test purpose;

a test purpose that arises from the requirements that are implicit in an application protocol and derived from usage scenarios and the process and information flows in the application domain of an application protocol.

3.4.5

external reference test purpose

test purpose derived from requirements that arise from standards referenced by an application protocol.

a test purpose derived from the AIM EXPRESS schema of an application protocol.

3.4.6

input specification

the instance model of an abstract test case presented in an unambiguous form, the table format for preprocessors and physical files (ISO 10303-21).

3.5 Abbreviations

ΑE application element

AIM application interpreted model

AP application protocol

ARM application reference model

ATS abstract test suite

CC conformance class

IUT implementation under test

technical data package iTeh Standards **TDP**

unit of functionality DS://standards.iteh.ai) UoF

4 Test purposes

NOTE 1 Portions of this clause have been written in accordance with the Guidelines for the development of abstract test suites [1]. 9/standards/iso/310922

This clause specifies the test purposes for this part of ISO 10303. Clauses 4.1 and 4.2 describe the source and meaning of test purposes that are derived from the information requirement defined in ISO 10303-232, clause 4, and the AIM EXPRESS schema defined in ISO 10303-232, annex A. Each test purpose statement identifies some specific element from the application elements or the AIM. Every test purpose statement implicitly requires that the identified element, as specified in the test purpose statement, will be correctly instantiated by the implementation under test in at least one test case within the test suite.

Implementation method test purposes in 4.3 are derived from ISO 10303-21. Domain test purposes in 4.4 are derived from implicit domain requirements in the AP that are not clearly specified at the application element level. The primary source of these implicit domain requirements is optional mappings specified in ISO 10303-232, clause 5.1. Implementation method and domain test purposes are individually identified by the prefix "other" in the test purpose number. These test purposes are statements of requirements that shall be met by a conforming implementation.

NOTE 2 Not all test purposes are covered by an abstract test case in clause 6 of this edition of this part of ISO 10303. Additional test cases will be added to a future edition to provide more complete coverage of the test purposes.